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**NATIONAL STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

GB/T 17554.1-2025

**Cards and security devices for personal identification - Test
methods - Part 1: General characteristics**
(English Translation)

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Table of Contents

Preface	
Introduction	
1 Scope	
2 Normative references	
3 Terms, definitions and abbreviations	
3.1 Terms and Definitions	
3.2 Abbreviations	
4 Defaults for test methods	
4.1 Test Environment	
4.2 Preprocessing	
4.3 Test method selection	
4.4 Default Tolerance	
4.5 Total measurement uncertainty	
5 Test Method	
5.1 Card Warping	
5.2 Card size	
5.3 Peel strength	
5.4 Peel strength including card edge	
5.5 Chemical resistance	
5.6 Card Dimensional Stability and Warpage under Temperature and Humidity Conditions	
5.7 Adhesion or block	
5.8 Flexural toughness	
5.9 Dynamic bending stress	
5.10 Dynamic torsional stress	
5.11 Opacity	
5.12 Ultraviolet	
5.13 X-ray	
5.14 Height of embossed characters	
5.15 Heat resistance	
5.16 Surface distortion, raised areas and sunken areas	
5.17 Toxic and hazardous substances content	

6 Test methods for IC cards

6.1 Electrical Measurement Conventions for IC Cards with Contacts

6.2 IC card measurement device with contacts

6.3 IC card with contacts, contact size and position

6.4 Mechanical strength of contacts

6.5 ESD --- Electrostatic Discharge on IC Cards with Contacts

6.6 ESS---Electrostatic stress on PICC and VICC

6.7 Surface resistance of IC card contacts with contacts

6.8 Surface profile of IC card contacts with contacts

6.9 IC card---Mechanical strength. Three rounds of test for IC cards with contacts

References

Figure 1 Warpage measurement device

Figure 2 Quadrant Distribution

Figure 3 Card preparation

Figure 4 Sample preparation for peel test

Figure 5 Sample installed in the tensile tester

Figure 6 Peel strength graph recording example

Figure 7 Stabilizing plate (top and side views)

Figure 8 Guide rail (end view)

Figure 9 Card preparation

Figure 10 Sample preparation for peel test

Figure 11 Sample and stabilizing plate installed in the tensile tester

Figure 12 Example of adjacent negative and positive spikes

Figure 13 Peel strength graph recording example

Figure 14. Card 17 in the fixture before loading

Figure 15. Card in the fixture during loading

Figure 16 Card 18 in the fixture after the load is removed

Figure 17 Dynamic bending test equipment

Figure 18 Definition of axis

Figure 19 Twist test machine

Figure 20 Pressure cycle function

Figure 21. Each area for measuring light opacity

Figure 22 Card 25 in the clamping device before exposure to temperature

Figure 23 Card 26 in clamping device after exposure to temperature

Figure 24 IC card holder

Figure 25 Flat plate

Figure 26 The position of the IC card and the flat plate on the fixture

Figure 27 Default IC card holder and flat plate 30 with positioning template and steel ball or round tip assembly

Figure 28 Positioning template

Figure 29 ESD test circuit

Figure 30 ESD test area of PICC or VICC

Figure 31 Test probe

Figure 32 Measuring probe

Figure 33 Measurement line 35 from C1 to C5

Figure 34 Three-round test principle

Figure 35 The position of the roller and the initial position of the IC card

Figure 36 Position of axis A, axis B and axis C

Figure 37 Insertion position of IC card

Table 1 Short-term effects of reagent

Table 2 Long-term effects of reagents

Table 3 Bending dimensions around axis A

Table 4 Bending dimensions around axis B

Foreword

This document is in accordance with the provisions of GB/T 1.1-2020 "Guidelines for standardization work Part 1: Structure and drafting rules for standardization documents" Drafting.

This document is Part 1 of GB/T 17554. GB/T 17554 has been published in the following parts.

- Test methods for cards and identity security devices Part 1: General characteristics;
- Identification card test methods Part 2: Cards with magnetic stripe;
- Identification card test methods Part 3: Integrated circuit cards with contacts and related interface devices;
- Identification card test methods Part 7: Proximity cards.

This document replaces GB/T 17554.1-2006 "Identification card test method Part 1: General characteristics test" and Compared with GB/T 17554.1-2006, in addition to structural adjustments and editorial changes, the main technical changes are as follows.

- Added terms and definitions such as "basic standard", "electrostatic discharge" and

"electrostatic stress" (see 3.1.12, 3.1.13, 3.1.14);

--- Deleted the terms and definitions such as "flammability", "< light> transmittance", "transmittance density" and "normal use" (see 3.12, 2006 edition) 3.13, 3.14, 3.15);

--- Deleted "select the test according to the characteristics presented by the card" (see Table 1 of the 2006 edition);

--- Changed "total measurement uncertainty" to "total measurement uncertainty" (see 4.5, 4.5 of the 2006 edition);

--- Deleted the "flammability" and "static magnetic field" test methods (see 5.10 and 5.14 of the 2006 edition);

--- Added "peel strength including card edge", "surface distortion, raised area and recessed area", "toxic and hazardous substance content" tests Methods (see 5.4, 5.16, 5.17);

--- Technical improvements have been made to the dynamic bending stress calibration method, and "calibration method" has been added (see 5.9.3, 5.8 of the 2006 edition);

--- Changed the "Opacity" spectral measurement range to meet the requirements of the basic standard GB/T 14916-2022 (see 5.11, 2006 Version 5.11);

--- Added "Test methods for IC cards" (see Chapter 6).

This document is modified to adopt ISO/IEC 10373-1:2020 "Test methods for cards and identity security devices - Part 1: General characteristics" sex".

This document has the following structural adjustments compared to ISO/IEC 10373-1:2020.

--- Add 5.12 (ultraviolet rays) and 5.17 (toxic and hazardous substances content), delete 3.1.12, 3.1.16, 6.8, Appendix A, Appendix B, Figure 21, Figure 22 and Figure 23;

---3.1.12 corresponds to 3.1.13 in ISO/IEC 10373-1:2020;

---3.1.13 corresponds to 3.1.14 in ISO/IEC 10373-1:2020;

---3.1.14 corresponds to 3.1.15 in ISO/IEC 10373-1:2020;

---5.13 corresponds to 5.12 in ISO/IEC 10373-1:2020;

---5.14 corresponds to 5.13 in ISO/IEC 10373-1:2020;

---5.15 corresponds to 5.14 in ISO/IEC 10373-1:2020;

---5.16 corresponds to 5.15 in ISO/IEC 10373-1:2020;

---6.8 corresponds to 6.9 in ISO/IEC 10373-1:2020;

---6.9 corresponds to 6.10 in ISO/IEC 10373-1:2020.

The technical differences between this document and ISO/IEC 10373-1:2020 and their